#### **Features**

- Fast read access time 45ns
- Low-power CMOS operation
  - 100µA max standby
  - 30mA max active at 5MHz
- JEDEC standard packages
  - 40-lead PDIP
  - 44-lead PLCC
- Direct upgrade from 512K (Atmel® AT27C516) EPROM
- $5V \pm 10\%$  power supply
- High-reliability CMOS technology
  - 2000V ESD protection
  - 200mA latchup immunity
- Rapid programming algorithm 100µs/word (typical)
- CMOS- and TTL-compatible inputs and outputs
- Integrated product identification code
- Industrial and automotive temperature ranges
- Green (Pb/halide-free) packaging option

### 1. Description

The Atmel AT27C1024 is a low-power, high-performance 1,048,576-bit, one-time programmable, read-only memory (OTP EPROM) organized as 64K by 16 bits. It requires only one 5V power supply in normal read mode operation. Any word can be accessed in less than 45ns, eliminating the need for speed reducing WAIT states. The x16 organization makes this part ideal for high-performance, 16- and 32-bit microprocessor systems.

In read mode, the AT27C1024 typically consumes 15mA. Standby mode supply current is typically less than  $10\mu$ A.

The AT27C1024 is available in industry-standard, JEDEC-approved, one-time programmable (OTP) PDIP and PLCC packages. The device features two-line control ( $\overline{\text{CE}}$ ,  $\overline{\text{OE}}$ ) to eliminate bus contention in high-speed systems.

With high-density, 64K word storage capability, the AT27C1024 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

The AT27C1024 has additional features to ensure high quality and efficient production use. The rapid programming algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100µs/word. The integrated product identification code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.



1Mb (64K x 16)
One-time
Programmable
Read-only Memory

Atmel AT27C1024

0019N-EPROM-4/11

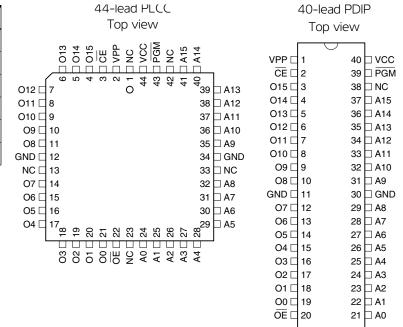




### 2. Pin configurations

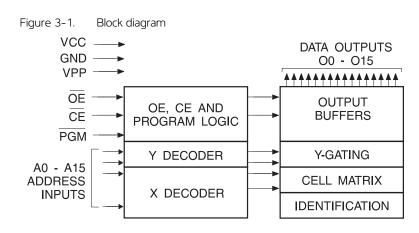
Pin name	Function
A0 - A15	Addresses
00 - 015	Outputs
CE	Chip enable
ŌĒ	Output enable
PGM	Program strobe
NC	No connect





### 3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device nonconformance. At a minimum, a  $0.1\mu\text{F}$ , high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the  $V_{CC}$  and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a  $4.7\mu\text{F}$  bulk electrolytic capacitor should be utilized, again connected between the  $V_{CC}$  and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.



### 4. Absolute maximum ratings\*

Temperature under bias55°C to + 125°C	
Storage temperature65°C to + 150°C	
Voltage on any pin with respect to ground2.0V to + 7.0V <sup>(1)</sup>	
Voltage on A9 with respect to ground2.0V to + 14.0V <sup>(1)</sup>	
V <sub>pp</sub> supply voltage with respect to ground2.0V to + 14.0V <sup>(1)</sup>	

\*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating

conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is  $V_{CC} + 0.75V$  DC, which may overshoot to +7.0V for pulses of less than 20ns.

### 5. DC and AC characteristics

Table 5-1. Operating modes

Mode/Pin	CE	ŌĒ	PGM	Ai	V <sub>PP</sub>	Outputs
Read	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	Ai	X	D <sub>OUT</sub>
Output disable	Х	V <sub>IH</sub>	Х	X	Х	High Z
Standby	V <sub>IH</sub>	Х	X	X	X <sup>(5)</sup>	High Z
Rapid program <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Ai	V <sub>PP</sub>	D <sub>IN</sub>
PGM verify	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Ai	V <sub>PP</sub>	D <sub>OUT</sub>
PGM inhibit	V <sub>IH</sub>	Х	X	X	V <sub>PP</sub>	High Z
Product identification <sup>(4)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	X	$A9 = V_H^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A15 = V_{IL}$	V <sub>CC</sub>	Identification code

Notes:

- X can be V<sub>IL</sub> or V<sub>IH</sub>.
- 2. Refer to programming characteristics.
- 3.  $V_H = 12.0 \pm 0.5 V$ .
- 4. Two identifier words may be selected. All Ai inputs are held low  $(V_{IL})$ , except A9, which is set to  $V_{H}$ , and A0, which is toggled low  $(V_{IL})$  to select the manufacturer's identification word and high  $(V_{IH})$  to select the device code word.
- 5. Standby  $V_{CC}$  current ( $I_{SB}$ ) is specified with  $V_{PP} = V_{CC}$ .  $V_{CC} > V_{PP}$  will cause a slight increase in  $I_{SB}$ .

Table 5-2. DC and AC operating conditions for read operation

		Atmel A	T27C1024
		-45	-70
On anting town (and )	Ind.	-40°C - 85°C	-40°C - 85°C
Operating temp. (case)	Auto.		
V <sub>CC</sub> power supply		5V ± 10%	5V ± 10%





Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition	Condition			Units
	lanut load current	)/ 0)/ to //	Ind.		±1	μA
I <sub>LI</sub>	Input load current	$V_{IN} = OV \text{ to } V_{CC}$	Auto.		±5	μA
	Output leakage gurrent	0//+0//	Ind.		±5	μA
ILO	Output leakage current	$V_{OUT} = 0V \text{ to } V_{CC}$	Auto.		±10	μΑ
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1))</sup> read/standby current	$V_{PP} = V_{CC}$	$V_{PP} = V_{CC}$			μA
	V (1) -tt	$I_{SB1}$ (CMOS), $\overline{CE} = V_C$	$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μΑ
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> standby current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V		1	mA
I <sub>CC</sub>	V <sub>CC</sub> active current	$f = 5MHz$ , $I_{OUT} = 0mA$	, CE = V <sub>IL</sub>		30	mΑ
V <sub>IL</sub>	Input low voltage			-0.6	0.8	V
V <sub>IH</sub>	Input high voltage			2.0	V <sub>CC</sub> + 0.5	V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 2.1mA	I <sub>OL</sub> = 2.1mA		0.4	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -400µA	I <sub>OH</sub> = -400μA			V

Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$ , and removed simultaneously with or after  $V_{PP}$ .

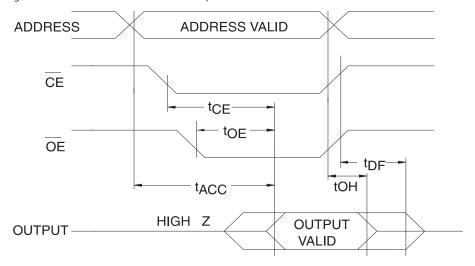
Table 5-4. AC characteristics for read operation

				Atmel AT27C1024				
			_	45	_	70		
Symbol	Parameter	Condition	Min	Max	Min	Max	Units	
t <sub>ACC</sub> <sup>(1)</sup>	Address to output delay	$\overline{CE} = \overline{OE} = V_{IL}$		45		70	ns	
t <sub>CE</sub> <sup>(1)</sup>	CE to output delay	OE = V <sub>IL</sub>		45		70	ns	
t <sub>OE</sub> <sup>(1)</sup>	OE to output delay	$\overline{CE} = V_{IL}$		20		25	ns	
t <sub>DF</sub> <sup>(1)</sup>	OE or CE high to output float, whichever occurred first			20		25	ns	
t <sub>OH</sub>	Output hold from address, $\overline{\text{CE}}$ or $\overline{\text{OE}}$ , whichever occurred first				7		ns	

Note: 1. See AC waveforms for read operation.

<sup>2.</sup>  $V_{PP}$  may be connected directly to  $V_{CC}$ , except during programming. The supply current would then be the sum of  $I_{CC}$  and  $I_{PP}$ .

Figure 5-1. AC waveforms for read operation<sup>(1)</sup>



Notes:

- 1. Timing measurement reference level is 1.5V for -45. Input AC drive levels are  $V_{IL} = 0.0V$  and  $V_{IH} = 3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL} = 0.8V$  and  $V_{OH} = 2.0V$ . Input AC drive levels are  $V_{IL} = 0.45V$  and  $V_{IH} = 2.4V$ .
- 2.  $\overline{OE}$  may be delayed up to  $t_{CE}$   $t_{OE}$  after the falling edge of  $\overline{CE}$  without impact on  $t_{CE}$ .
- 3.  $\overline{\text{OE}}$  may be delayed up to  $t_{\text{ACC}}$   $t_{\text{OE}}$  after the address is valid without impact on  $t_{\text{ACC}}$ .
- 4. This parameter is only sampled, and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

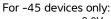
Table 5-5. Pin capacitance

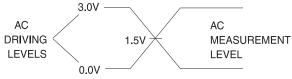
 $f = 1MHz, T = 25°C^{(1)}$ 

Symbol	Тур	Max	Units	Conditions
C <sub>IN</sub>	4	10	pF	V <sub>IN</sub> = 0V
C <sub>OUT</sub>	8	12	pF	V <sub>OUT</sub> = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

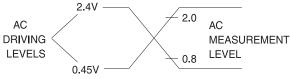
Figure 5-2. Input test waveforms and measurement levels





 $t_R$ ,  $t_F$  < 5ns (10% to 90%)

For -70 devices only:

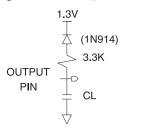


 $t_{\rm R},\,t_{\rm F}$  < 20 ns (10% to 90%)



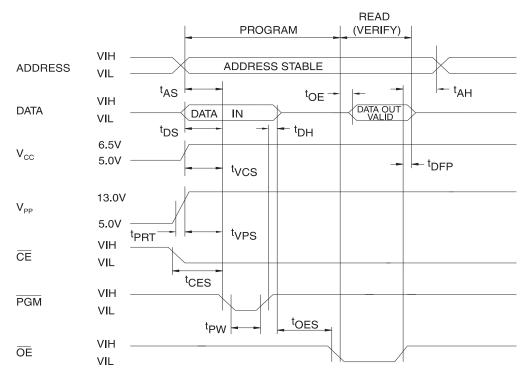


Figure 5-3. Output test load



Note: 1.  $C_L = 100 pF$  including jig capacitance, except -45 devices, where  $C_L = 30 pF$ .

Figure 5-4. Programming waveforms (1)



Notes:

- 1. The input timing reference is 0.8V for  $\rm V_{IL}$  and 2.0V for  $\rm V_{IH}$
- 2.  $t_{\text{OE}}$  and  $t_{\text{DFP}}$  are characteristics of the device, but must be accommodated by the programmer.
- 3. When programming the Atmel AT27C1024, a  $0.1\mu F$  capacitor is required across  $V_{pp}$  and ground to suppress sputious voltage transients.

Table 5-6. DC programming characteristics

$$T_A = 25 \pm 5$$
°C,  $V_{CC} = 6.5 \pm 0.25$ V,  $V_{PP} = 13.0 \pm 0.25$ V

			Limits		
Symbol	Parameter	Test conditions	Min	Max	Units
ILI	Input load current	$V_{IN} = V_{IL}, V_{IH}$		±10	μΑ
V <sub>IL</sub>	Input low level		-0.6	0.8	V
V <sub>IH</sub>	Input high level		2.0	V <sub>CC</sub> + 0.1	V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 2.1mA		0.4	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -400μA	2.4		V
I <sub>CC2</sub>	V <sub>CC</sub> supply current (program and verify)			50	mA
I <sub>PP2</sub>	V <sub>pp</sub> supply current	$\overline{CE} = \overline{PGM} = V_{IL}$		30	mA
V <sub>ID</sub>	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

 $T_A = 25 \pm 5$  °C,  $V_{CC} = 6.5 \pm 0.25$ V,  $V_{PP} = 13.0 \pm 0.25$ V

			Lin		
Symbol	Parameter	Test conditions <sup>(1)</sup>	Min	Max	Units
t <sub>AS</sub>	Address setup time		2		μs
t <sub>CES</sub>	CE setup time		2		μs
t <sub>OES</sub>	OE setup time	Input rise and fall times	2		μs
t <sub>DS</sub>	Data setup time	(10% to 90%) 20ns	2		μs
t <sub>AH</sub>	Address hold time	Input pulse levels	0		μs
t <sub>DH</sub>	Data hold time	0.45V to 2.4V	2		μs
t <sub>DFP</sub>	OE high to output float delay <sup>(2)</sup>	Input timing reference level	0	130	ns
t <sub>VPS</sub>	V <sub>PP</sub> setup time	0.8V to 2.0V	2		μs
t <sub>VCS</sub>	V <sub>CC</sub> setup time		2		μs
t <sub>PW</sub>	PGM program pulse width <sup>(3)</sup>	Output timing reference level 0.8V to 2.0V	95	105	μs
t <sub>OE</sub>	Data valid from OE	0.00 10 2.00		150	ns
t <sub>PRT</sub>	V <sub>PP</sub> pulse rise time during programming		50		ns

Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously with or after  $V_{PP}$ .

- 2. This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
- 3. Program pulse width tolerance is  $100\mu \sec \pm 5\%$ .

Table 5-8. The Atmel AT27C1024 integrated product identification code

		Pins				Hex					
Codes	A0	015-08	07	06	O5	04	О3	02	01	00	data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device type	1	0	1	1	1	1	0	0	0	1	00F1

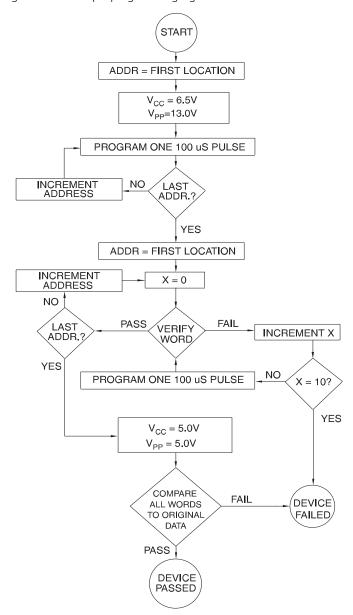




### 6. Rapid programming algorithm

A 100 $\mu$ s  $\overline{PGM}$  pulse width is used to program. The address is set to the first location.  $V_{CC}$  is raised to 6.5V and  $V_{PP}$  is raised to 13.0V. Each address is first programmed with one 100 $\mu$ s  $\overline{PGM}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 100 $\mu$ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked.  $V_{PP}$  is then lowered to 5.0V and  $V_{CC}$  to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1. Rapid programming algorithm



# 7. Ordering information

# Green Package (Pb/halide-free)

t <sub>ACC</sub>	I <sub>CC</sub> (mA)					
(ns)	Active	Standby	Atmel ordering code	Package	Lead finish	Operation range
45	30	0.1	AT27C1024-45JU AT27C1024-45PU	44J 40P6	Matte tin Matte tin	Industrial (-40°C to 85°C)
70	30	0.1	AT27C1024-70JU AT27C1024-70PU	44J 40P6	Matte tin Matte tin	Industrial (-40°C to 85°C)

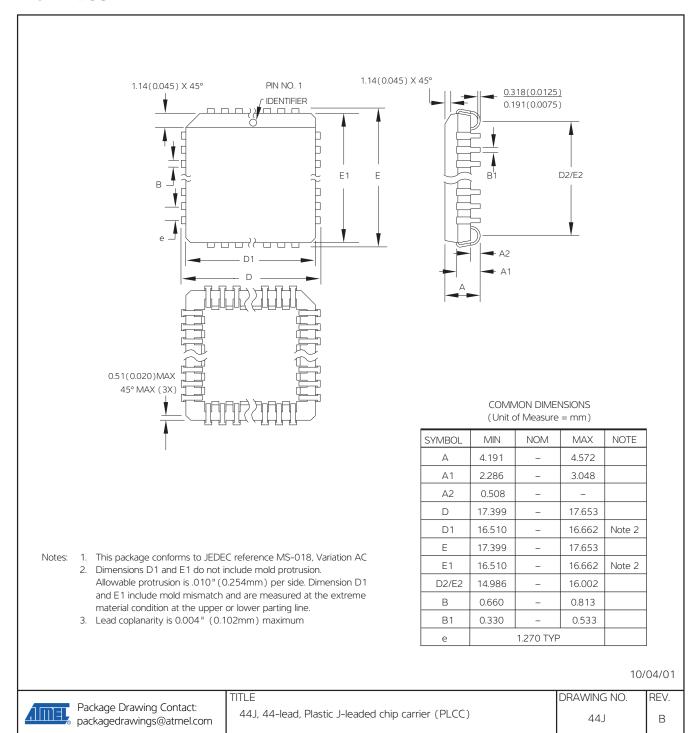
	Package type
44J	44-lead, plastic, J-leaded chip carrier (PLCC)
40P6	40-lead, 0.600" wide, plastic, dual inline package (PDIP)





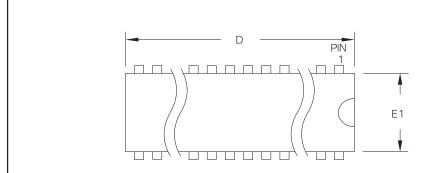
## 8. Packaging information

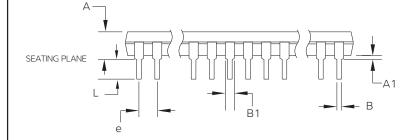
### 44J – PLCC

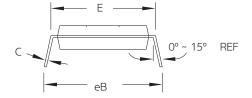


Atmel AT27C1024 ■

### 40P6 - PDIP







Notes: 1. This package conforms to JEDEC reference MS-011, Variation AC.

 Dimensions D and E1 do not include mold Flash or Protrusion. Mold Flash or Protrusion shall not exceed 0.25mm (0.010").

#### COMMON DIMENSIONS (Unit of Measure = mm)

(Unit of Measure = mm)				
SYMBOL	MIN	NOM	MAX	NOTE
А	-	-	4.826	
A1	0.381	_	_	
D	52.070	_	52.578	Note 2
Е	15.240	_	15.875	
E1	13.462	_	13.970	Note 2
В	0.356	-	0.559	
B1	1.041	_	1.651	
L	3.048	_	3.556	
С	0.203	_	0.381	
eB	15.494	_	17.526	
е	2.540 TYP			

09/28/01

Package Drawing Contact: packagedrawings@atmel.com

TITLE 40P6, 40-lead (0.600"/15.24mm Wide) Plastic Dual Inline Package (PDIP) DRAWING NO. 40P6 REV. B





# 9. Revision history

Doc. Rev.	Date	Comments
0019N	04/2011	Remove VSOP package Add lead finish to ordering information
0019M	12/2007	



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